

Abstract of the Disclosure

A semiconductor test system and method for the same. A handler is capable of moving and classifying semiconductor packages, a logic tester is capable of receiving a semiconductor package from the handler, and for testing a logic component of the semiconductor package. An analog tester may be coupled to the logic tester, where the analog tester is capable of testing an analog component of the semiconductor package. An interface unit may be included for selectively outputting a logic signal to enable the analog tester.